FZ シリコン結晶成長における非対称三相線の数値解析 Numerical analysis of asymmetric three-phase line in the floating zone silicon 九大応力研, ⁰韓 学峰, 中野智, 劉鑫, 原田 博文, 宮村 佳児, 柿本 浩一 RIAM, Kyushu Univ., [°] Xue-Feng Han, Satoshi Nakano, Xin Liu, Hirofumi Harada, Yoshiji Miyamura and Koichi Kakimoto

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Numerical calculation has been conducted to investigate the asymmetric heat transfer, fluid flow and three-phase line in the floating zone (FZ) silicon crystal growth. In the FZ method, a needle-eye inductor is used to grow the large-diameter (\geq 100 mm) single crystal silicon. The needle-eye inductor has one main slit and three side slits. This asymmetric configuration induces the asymmetric heating on the free surface of the silicon melt and three-phase line. R. Menzel et al. [1] observed that the spillage down of melt occurred during the crystal growth because of the inhomogeneous heating on the three-phase line. To investigate the effect of asymmetric heating on the deflection of three-phase line, electromagnetic (EM) and heat transfer calculations are conducted [2]. Fig. 1 shows that the current density distribution along the three-phase line is not homogeneous as a result of asymmetric high-frequency inductor. The asymmetric current density caused asymmetric heating and defection of three-phase line. The deflection of three-phase line is calculated to compare with the experimentally observed results (Fig. 2). Both the calculation and experimental results show a trend that along the rotation direction, the three-phase line descends quickly and ascends slowly below the current supplier. The inhomogeneous local growth rate at the three-phase line causes the asymmetric deflection of the three-phase line below the current supplier. When the local growth rate is lower than the pulling rate, the re-melting phenomenon occurs.



Fig. 1. Normalized surface current density distribution along the three phase line



Fig. 2. Comparison of the shape of the three-phase line between experimental observation results [1] and calculation results.

Reference

R. Menzel, Growth Conditions for Large Diameter FZ Si Single Crystals, PhD thesis, (2013).
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